WANSEMI
万芯半导体

WX040DE02DP

Enhancement Mode N-Channel Power MOSFET

DFN3X3/NMOS/18V/±12V/0.7V/15A/3.8mΩ

Rev0.5

18V, 3.8mΩ, 15A, Dual N-Channel MOSFET

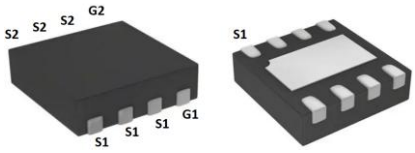
1.Features

- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package
- ESD Protected
- 100% RG Tested
- 100% UIS Tested

V_{DS} Typ.	$R_{DS(on)}$ Typ.	I_D Max.
18V	3.8mΩ @ 4.5V	15A
	4.8mΩ @ 2.5V	

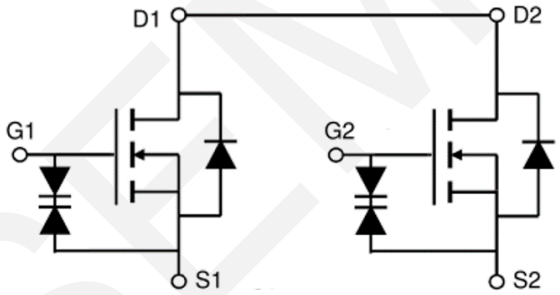
2.Applications

- Battery Protection
- Battery Powered Systems
- Power Management in Notebook Computer
- Portable Equipment



Pin Description

DFN3X3-8L



Schematic Diagram

3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX040DE02DP	040DE02	DFN3x3	5,000	50,000

4.Absolute Max Ratings at Ta=25℃ (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	18	V
Gate to Source Voltage	V_{GSS}	±12	V
Drain Current-Continuous	I_D	15	A
Drain Current (Pulse)	I_{DM}	60	A
Avalanche Energy, Single Pulsed	E_{AS}	138	mJ
Maximum Power Dissipation	P_D	3.0	W
Operating Junction and Storage Temperature Range	T_j, T_{stg}	-55 to +150	℃

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5.Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Maximum Junction-to-Ambien	$R_{\theta JA}$	41.7	℃/W

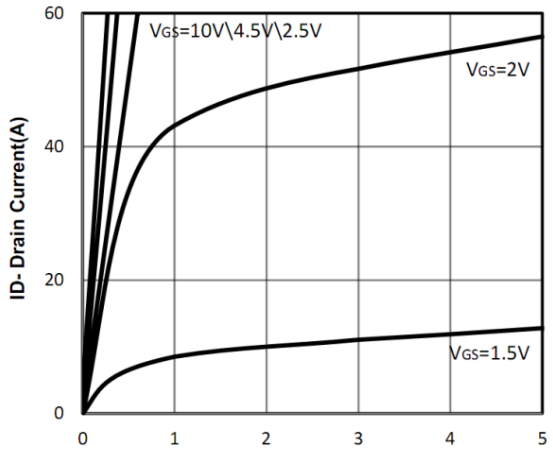
Note 2：When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

6.Electrical Characteristics at Ta=25℃ (Note 3)

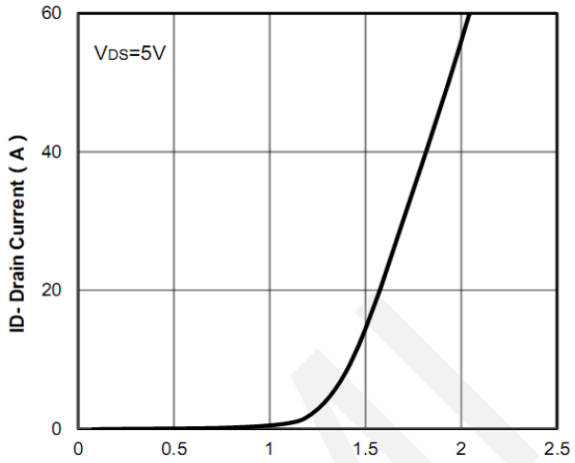
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	I_D = 250μA, V_{GS} = 0V	18	-	-	V
Zero-Gate Voltage Drain Current	I_{DSS}	V_{DS} = 18V, V_{GS} = 0V	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	V_{GS} = ±12V, V_{DS} = 0V	-	-	±10	μA
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_{DS}=250μA	0.5	0.7	1.2	V
Drain to Source On-State Resistance	$R_{DS(on)}$	I_D = 7A, V_{GS} = 4.5V	-	3.8	4.9	mΩ
		I_D = 3A, V_{GS} = 2.5V	-	4.8	6.1	mΩ
Input Capacitance	C_{iss}	V_{GS}=0V, V_{DS}=10V, Frequency=1.0MHz	-	1855	-	pF
Output Capacitance	C_{oss}		-	335	-	pF
Reverse Transfer Capacitance	C_{rss}		-	193	-	pF
Turn-ON Delay Time	$t_{d(on)}$	V_{DS} = 10V,V_{GS} = 5V, R_{GEN} = 3Ω,I_D=10A	-	4.1	-	ns
Turn-ON Rise Time	t_r		-	8	-	ns
Turn-OFF Delay Time	$t_{d(off)}$		-	76	-	ns
Turn-ON Fall Time	t_f		-	21	-	ns
Total Gate Charge	Q_g	V_{DS} = 10V, V_{GS} = 4.5V, I_D = 10A	-	24	-	nC
Gate-Source Charge	Q_{gs}		-	2.2	-	nC
Gate-Drain Charge	Q_{gd}		-	6.8	-	nC
Diode Forward Voltage	V_{SD}	I_S = 7A, V_{GS} = 0V	-	-	1.2	V

Note 3：Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

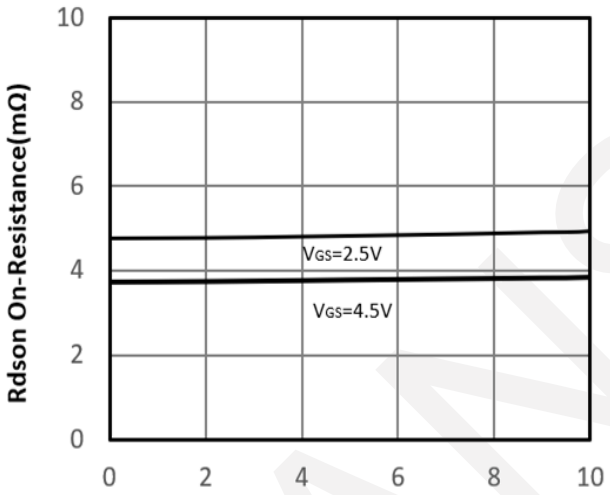
7.Typical electrical and thermal characteristics



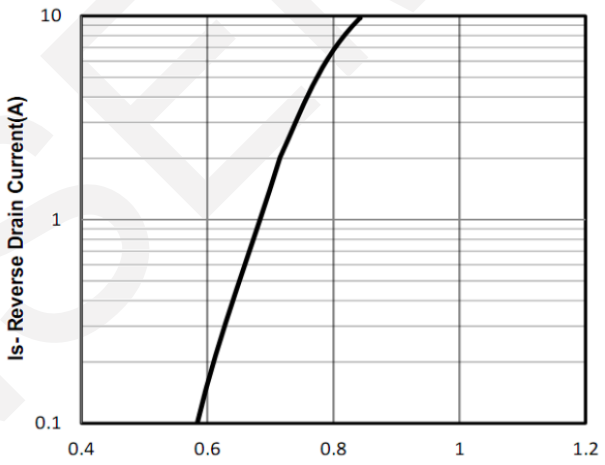
VDS –Drain Source Voltage（V）



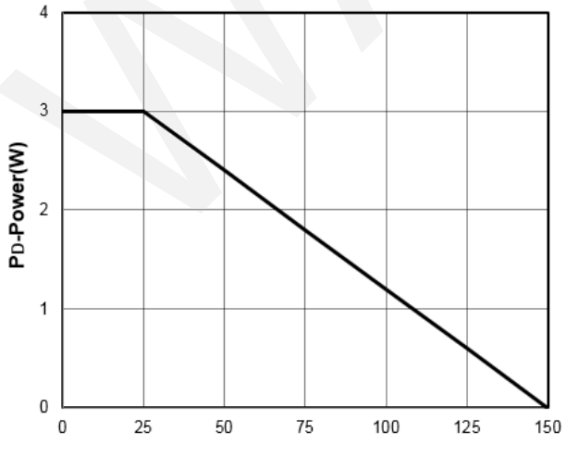
Vgs –Gate Source Voltage（V）



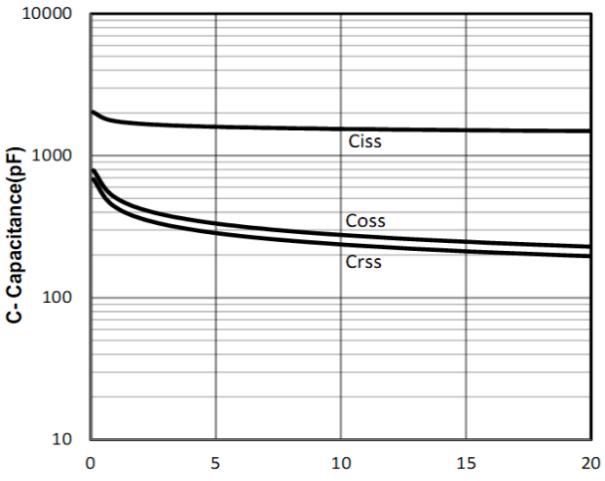
ID -Drain Current（A）



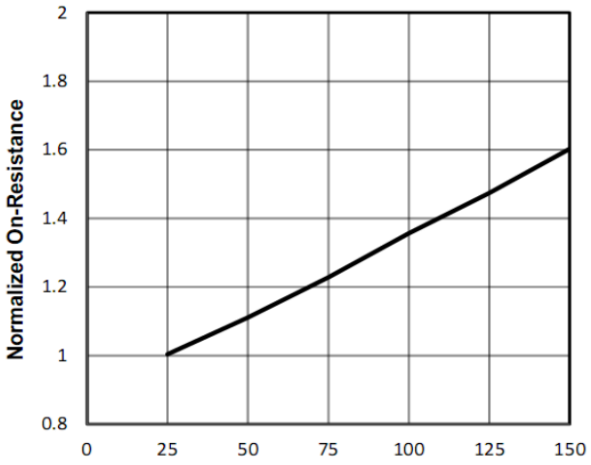
Vsd –Source Drain Voltage（V）



TJ -Junction Temperature（°C）



VDS –Drain Source Voltage（V）



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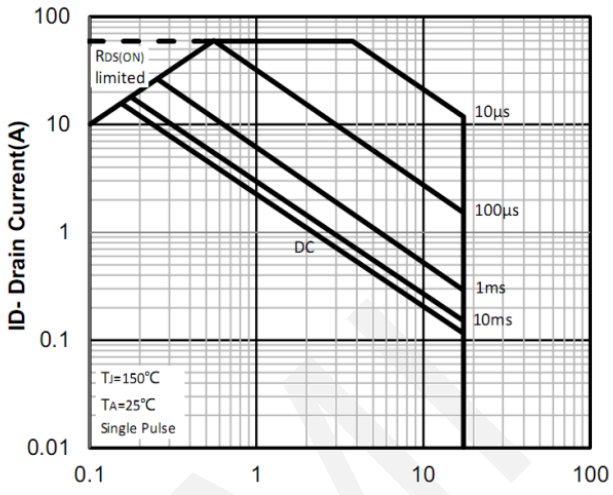

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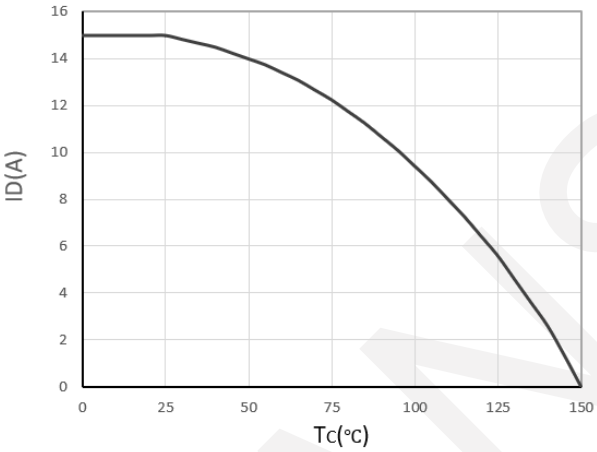

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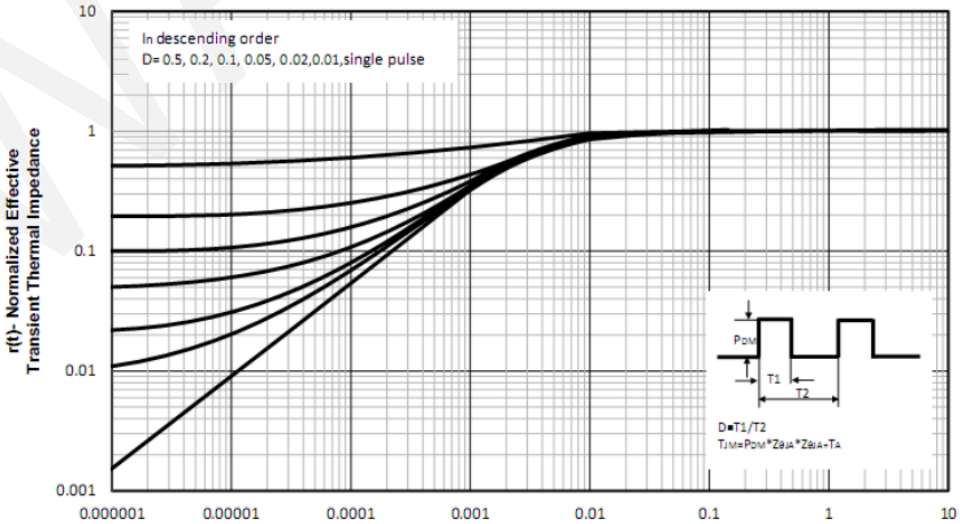
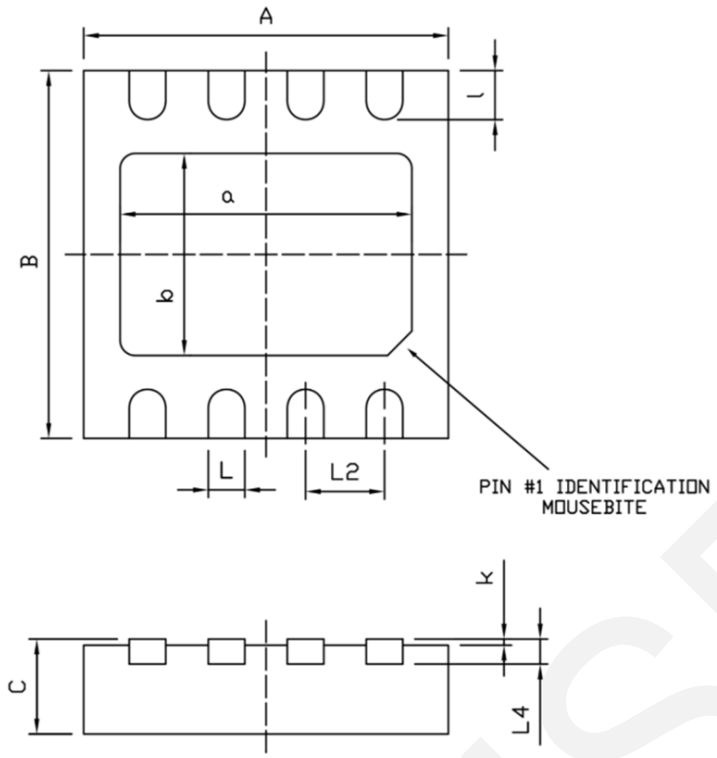


Square Wave Pulse Duration（sec）

8.Package Dimensions



Dimensions In Millimeterer			
Symbol	MIN	TYP	MAX
A	2.95	3.00	3.05
B	2.95	3.00	3.05
C	0.70	0.75	0.80
L	0.25	0.30	0.35
l	0.324	0.40	0.476
L2	–	0.65	–
L4	–	0.20	–
a	2.20	2.30	2.40
b	1.40	1.50	1.60
k	0.00	–	0.05

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